

Initial Comparisons between Solar EUV Spectral Irradiance Observations by SDO-EVE MEGS and TIMED-SEE

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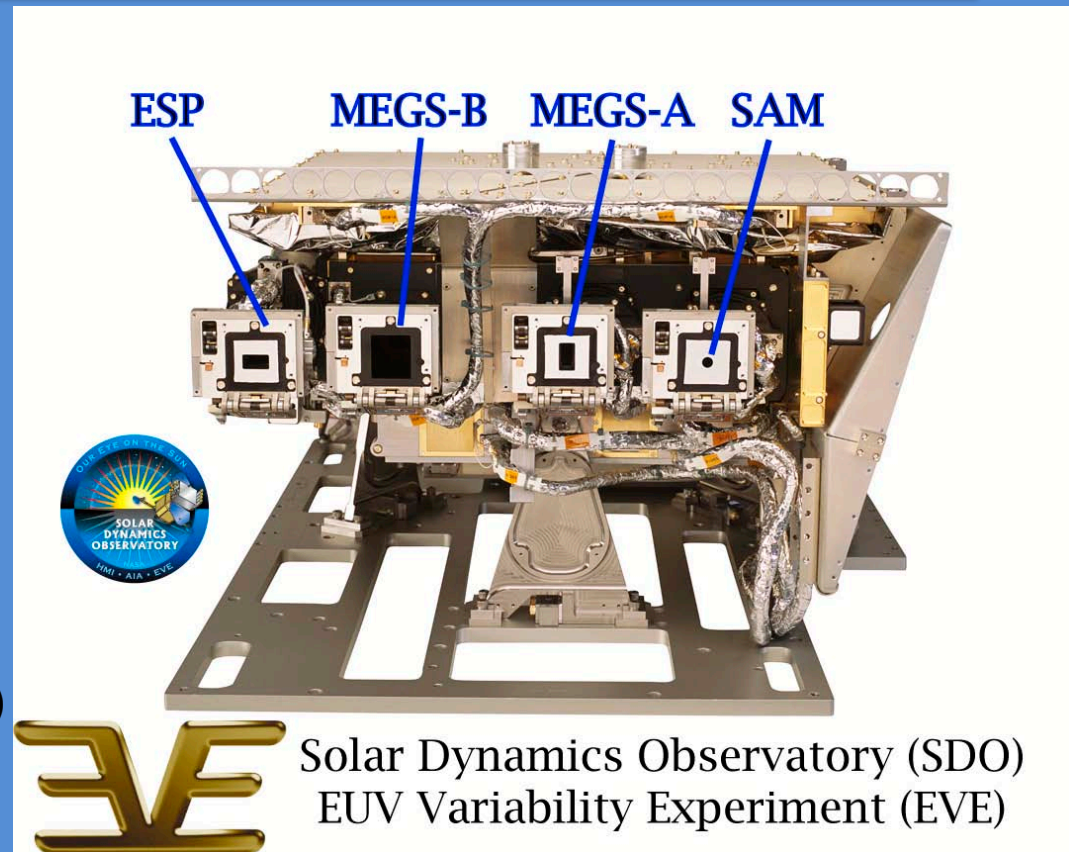


The Two Instruments

- EVE = EUV Variability Experiment
 - On NASA Solar Dynamics Observatory (SDO)
 - Making routine measurements since 03-May-2010
- SEE = Solar EUV Experiment
 - On NASA TIMED Mission
 - Making routine measurements since 22-Jan-2002

SDO-EVE Overview

- **Multiple EUV Grating Spectrograph (MEGS)**
 - *at 0.1 nm resolution*
MEGS-A: 5-37 nm
MEGS-B: 35-105 nm
 - *at 1 nm resolution*
MEGS-SAM: 0-7 nm
 - *at 10 nm resolution*
MEGS-Photometers: @ 122 nm
 - Ly- α Proxy for:
H I emissions at 80-102 nm
He I emissions at 45-58 nm
- **EUV Spectrophotometer (ESP)**
 - *at 4 nm resolution*
17.5, 25.6, 30.4, 36 nm
 - *at 7 nm resolution*
0-7 nm (zeroth order)
- In-flight calibrations from ESP and MEGS-P on daily basis and also annual calibration rocket flights



Measurement Cadence:

MEGS = full spectrum every 10-sec
ESP = broadbands every ¼-sec

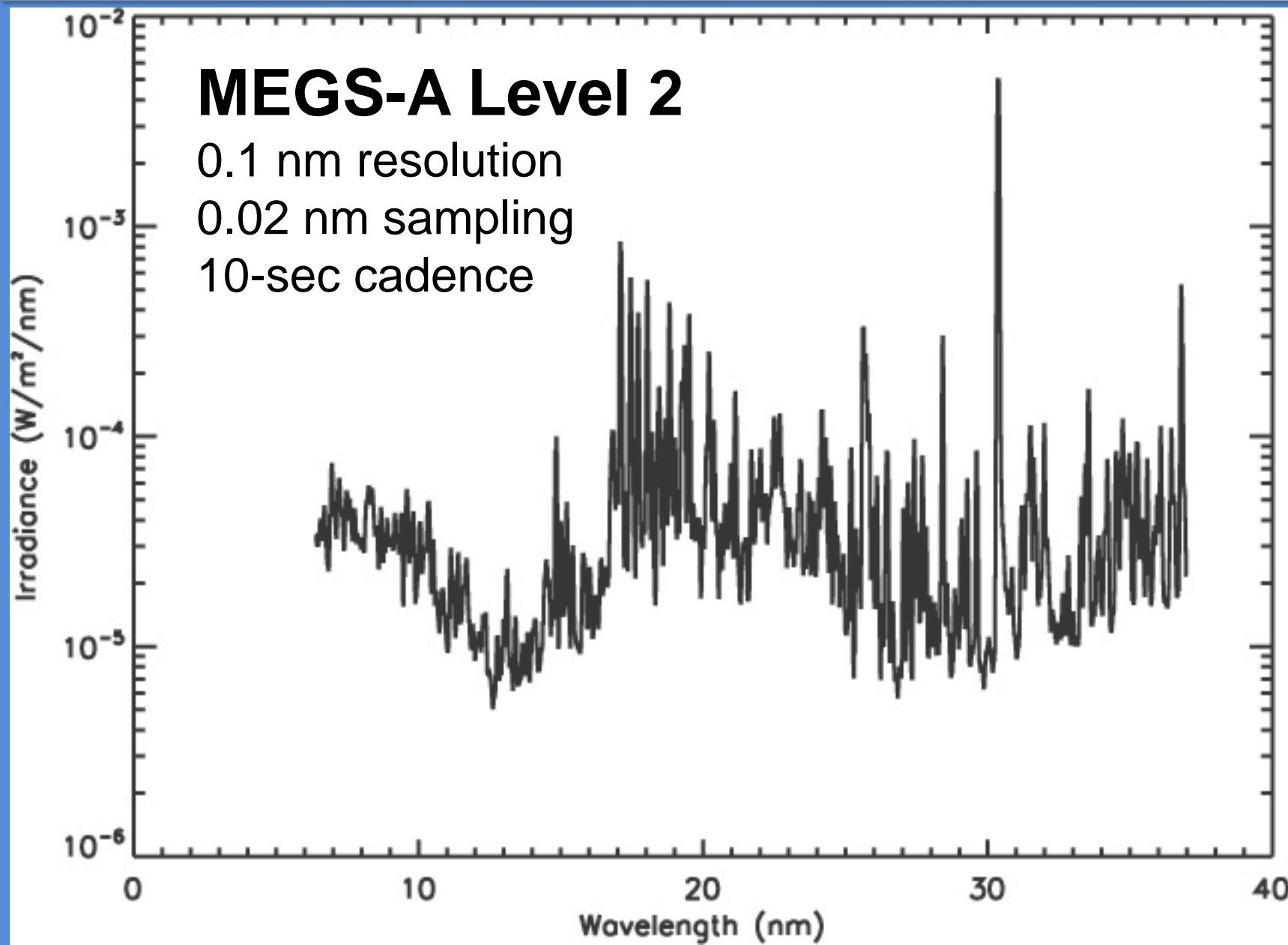
MEGS-A Data

MEGS-A Level 2

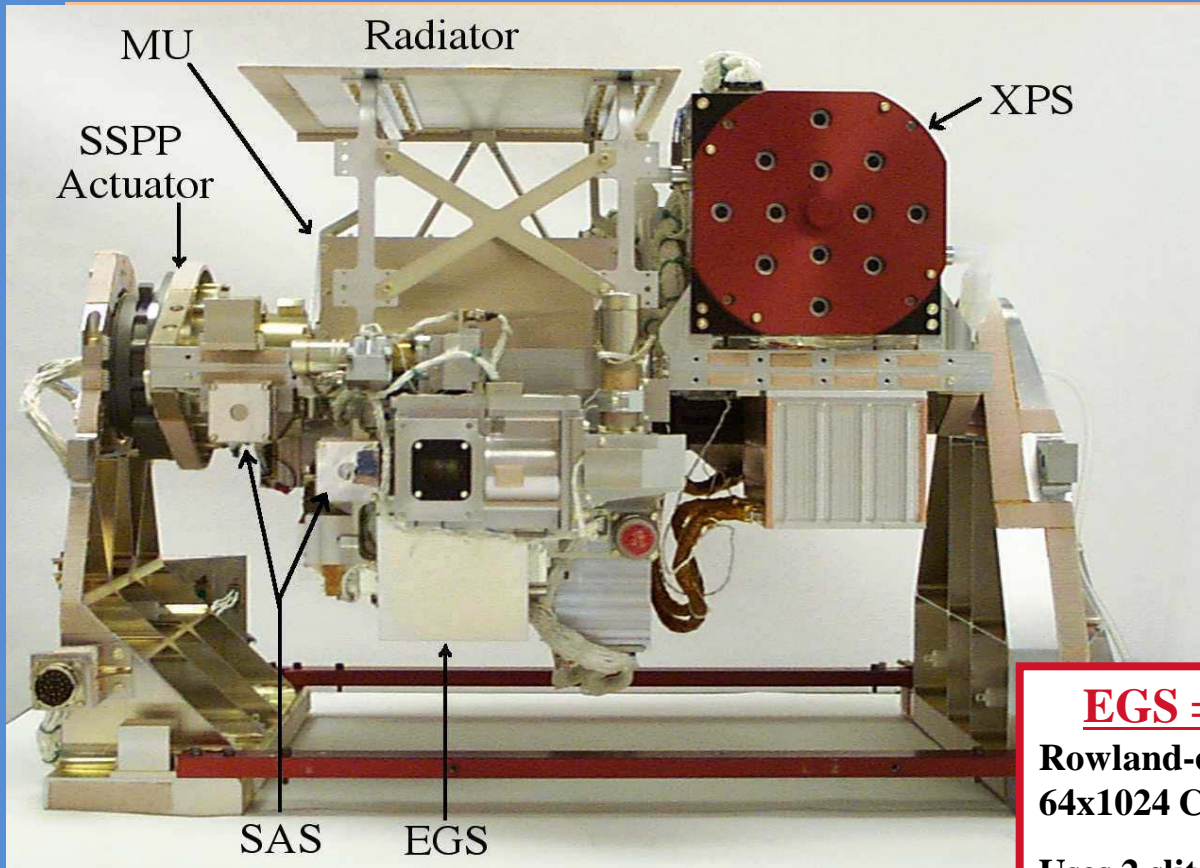
0.1 nm resolution

0.02 nm sampling

10-sec cadence



TIMED-SEE Overview



Measures the solar vacuum ultraviolet (VUV) irradiance

Range:

0.1-194 nm

Resolution:

0.4 nm EGS (27-194 nm)

5-10 nm XPS (0.1-34 nm)

Measurement Cadence:

10-sec integrations, but only for 3 min per orbit (96 min)

EGS = EUV Grating Spectrograph

Rowland-circle grating spectrograph with 64x1024 CODACON (MCP-based) detector

Uses 2 slits to provide redundant measurements

XPS = XUV Photometer System

Set of 12 Si photodiodes - 8 for XUV, 1 for Ly- α , and 3 for window calibrations

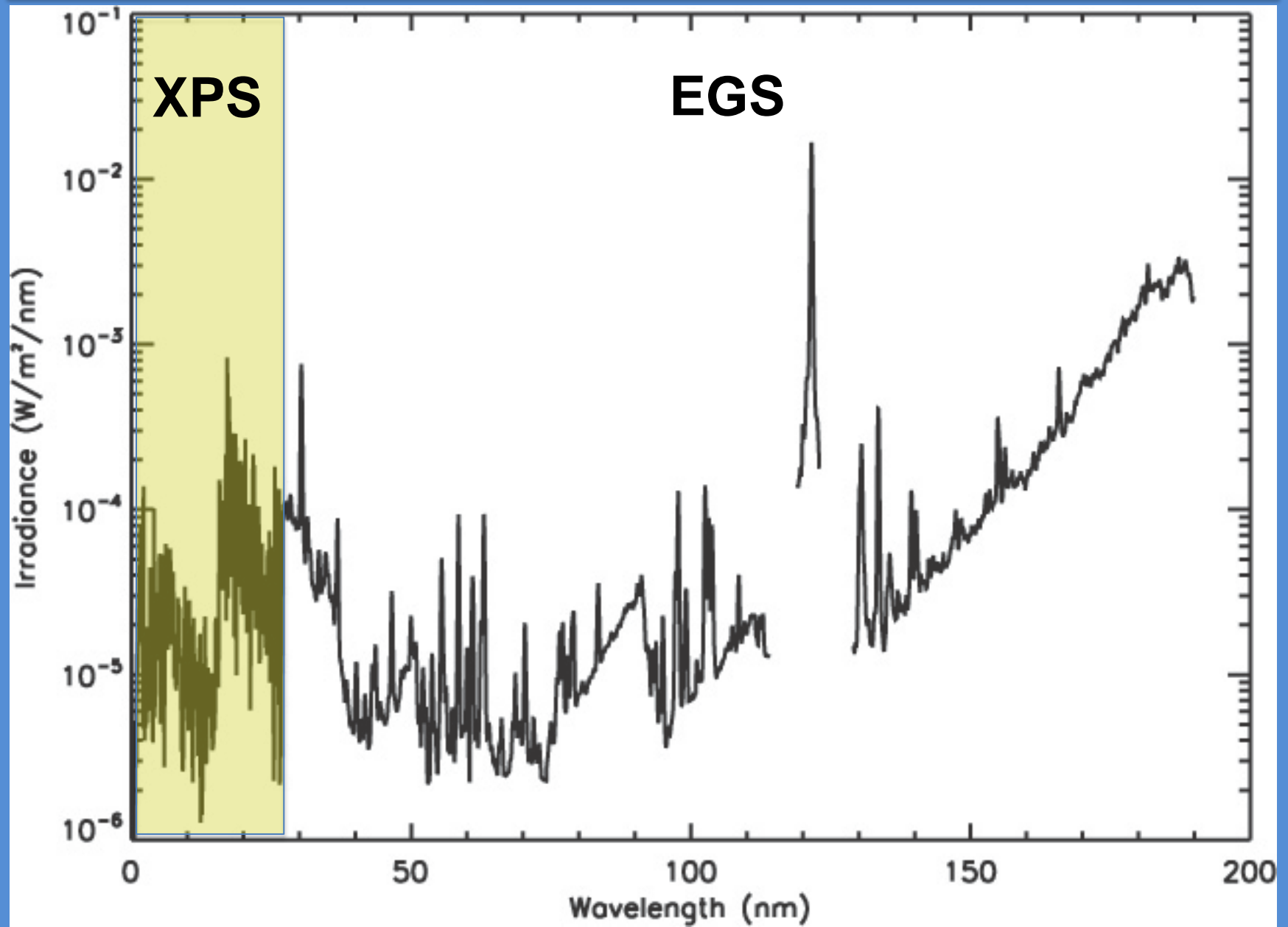
Includes 3 redundant photodiodes

MU = Microprocessor Unit

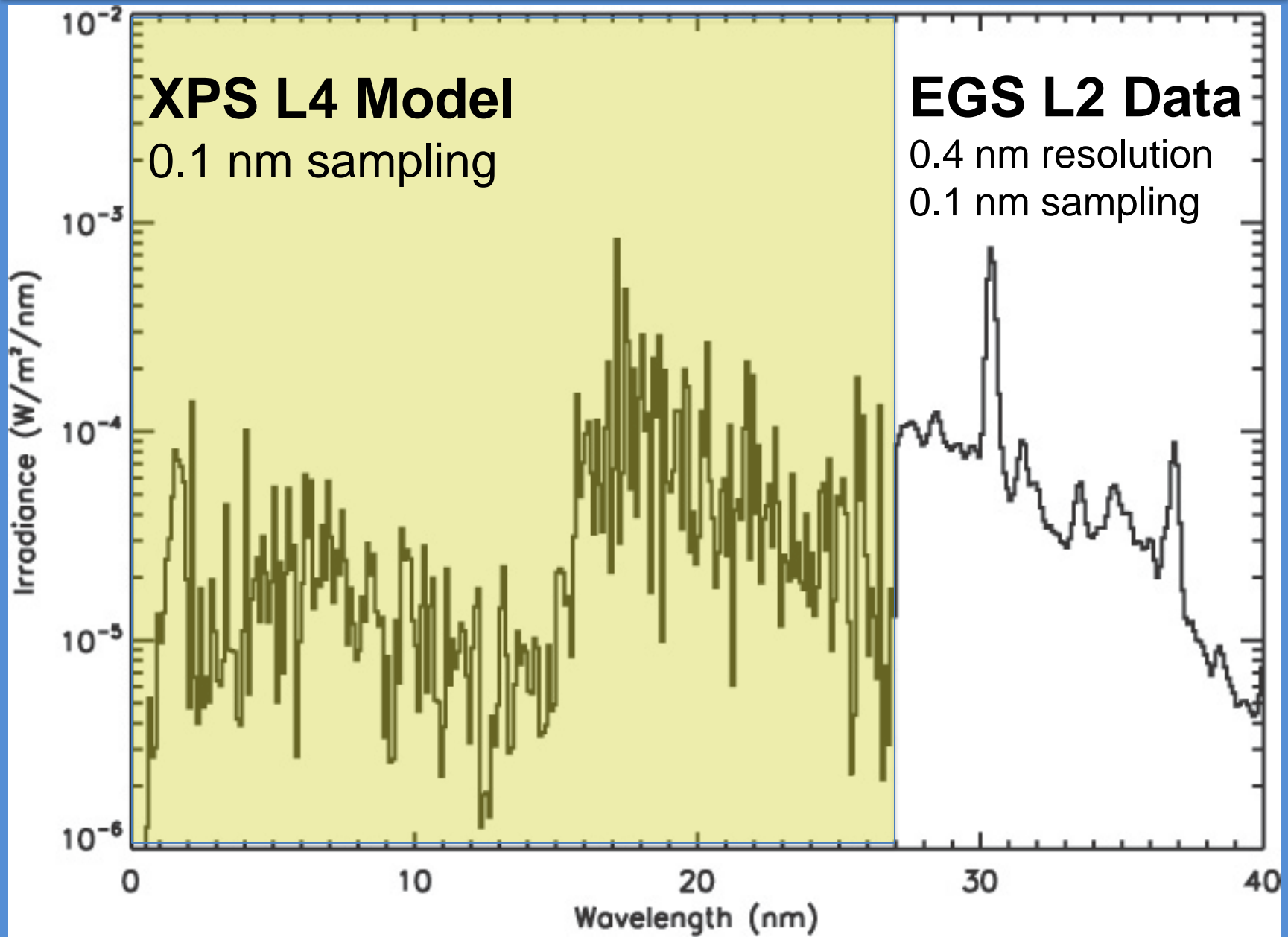
SSPP = SEE Solar Pointing Platform

SAS = Solar Aspect Sensor (2)

SEE Spectrum



SEE and MEGS-A Overlap Region

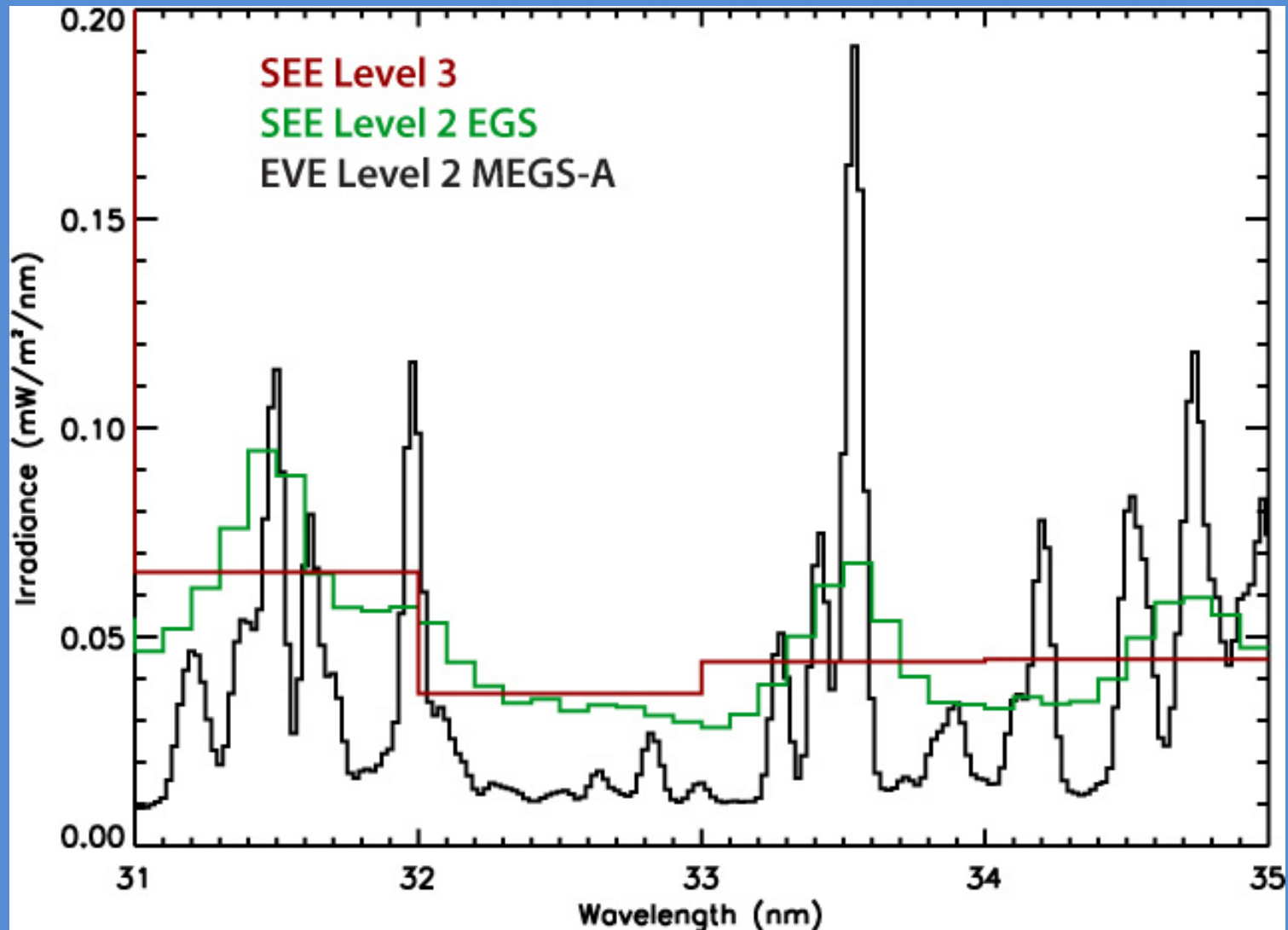


Comparing Two Different Instruments

- Not straight forward due to differences in:
 - Wavelength resolution
 - SEE EGS L2 spectral resolution = 0.4 nm, sampling = 0.1 nm
 - SEE L3 data product in 1-nm bins
 - EVE MEGS spectral resolution = 0.1 nm, sampling = 0.02 nm
 - Time cadence
 - SEE Orbit Data (L2A, L3A, L4A) = 96-minutes
 - SEE Daily Data (L2, L3, L4) = 1-day (medianed)
 - EVE L2 data = 10-seconds

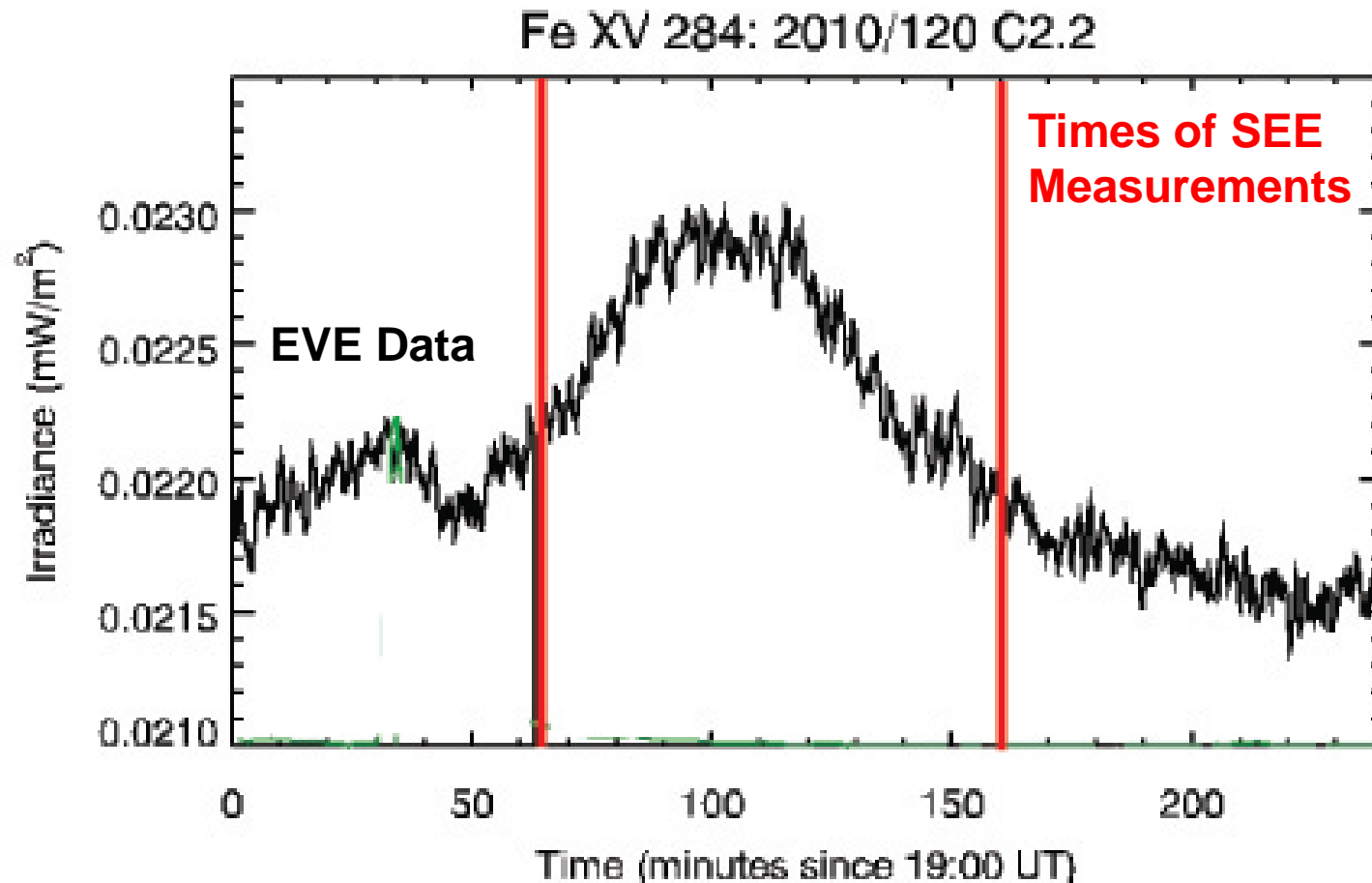
Different Wavelength Resolution/Binning

- Compare by binning? Convoluting? Both?

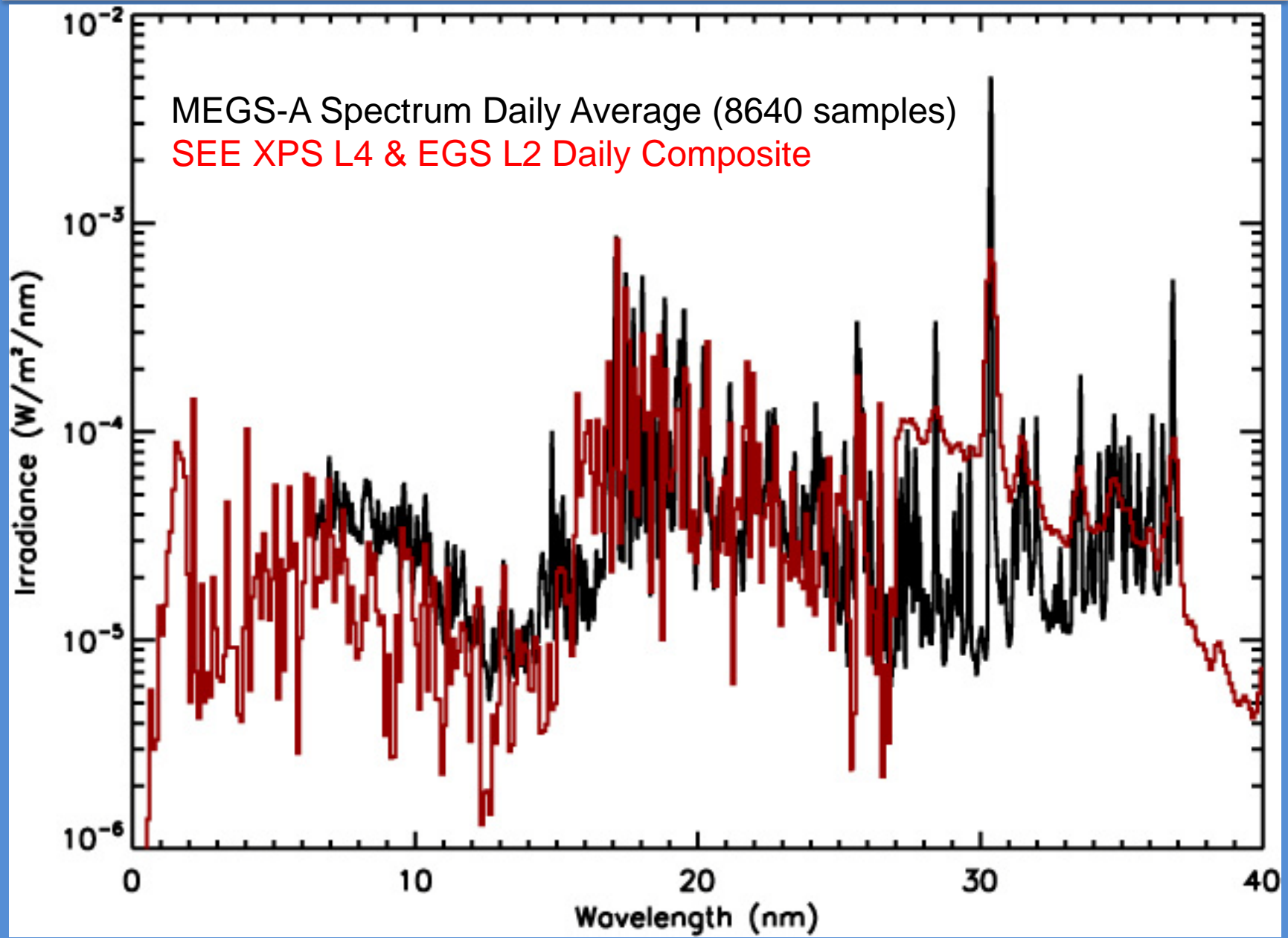


Different Time Sampling

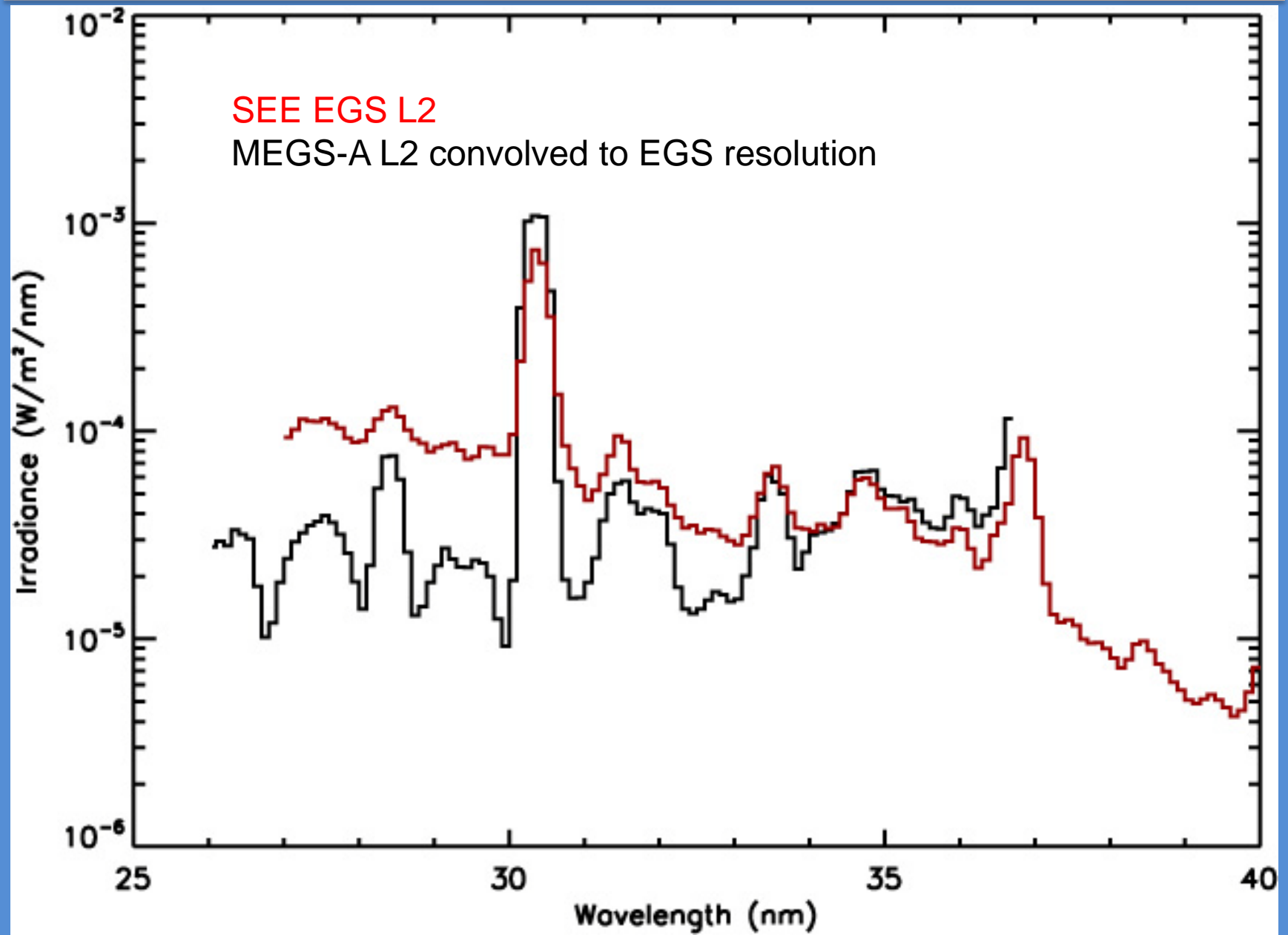
- Compare simultaneous samples? Daily averages? Weekly averages?



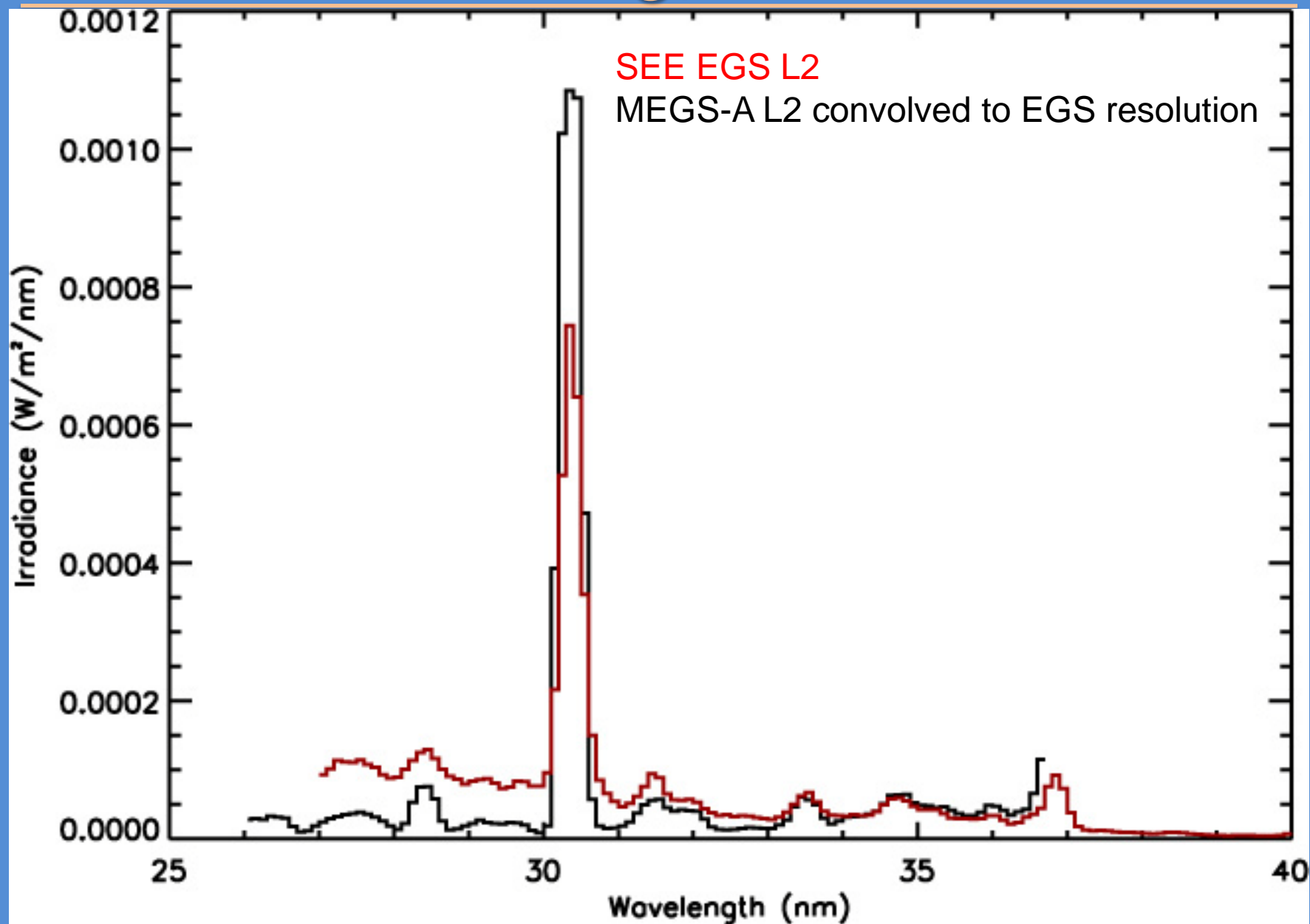
Simple Overplot for 03-May-2010



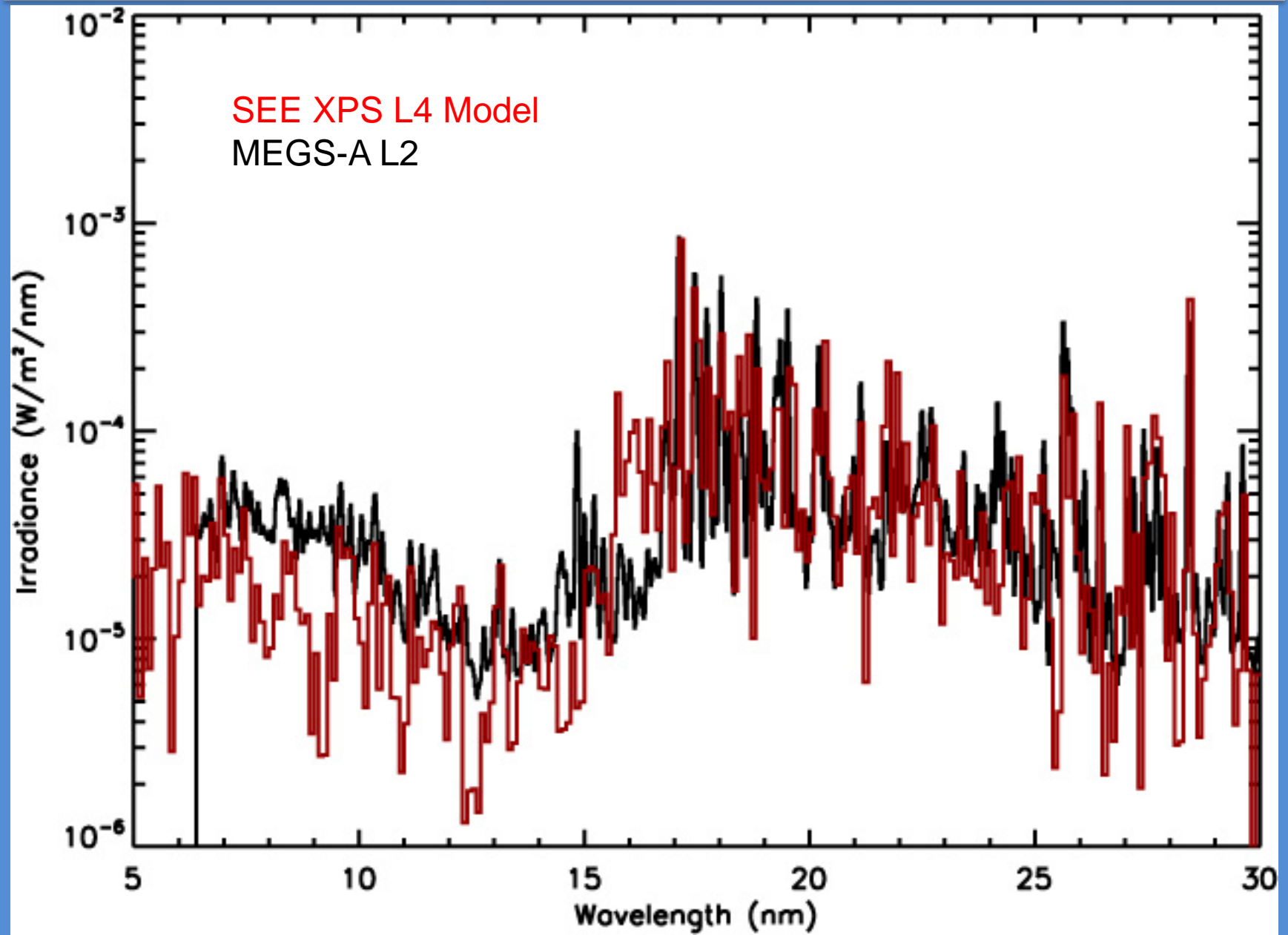
MEGS-A Converted to EGS L2



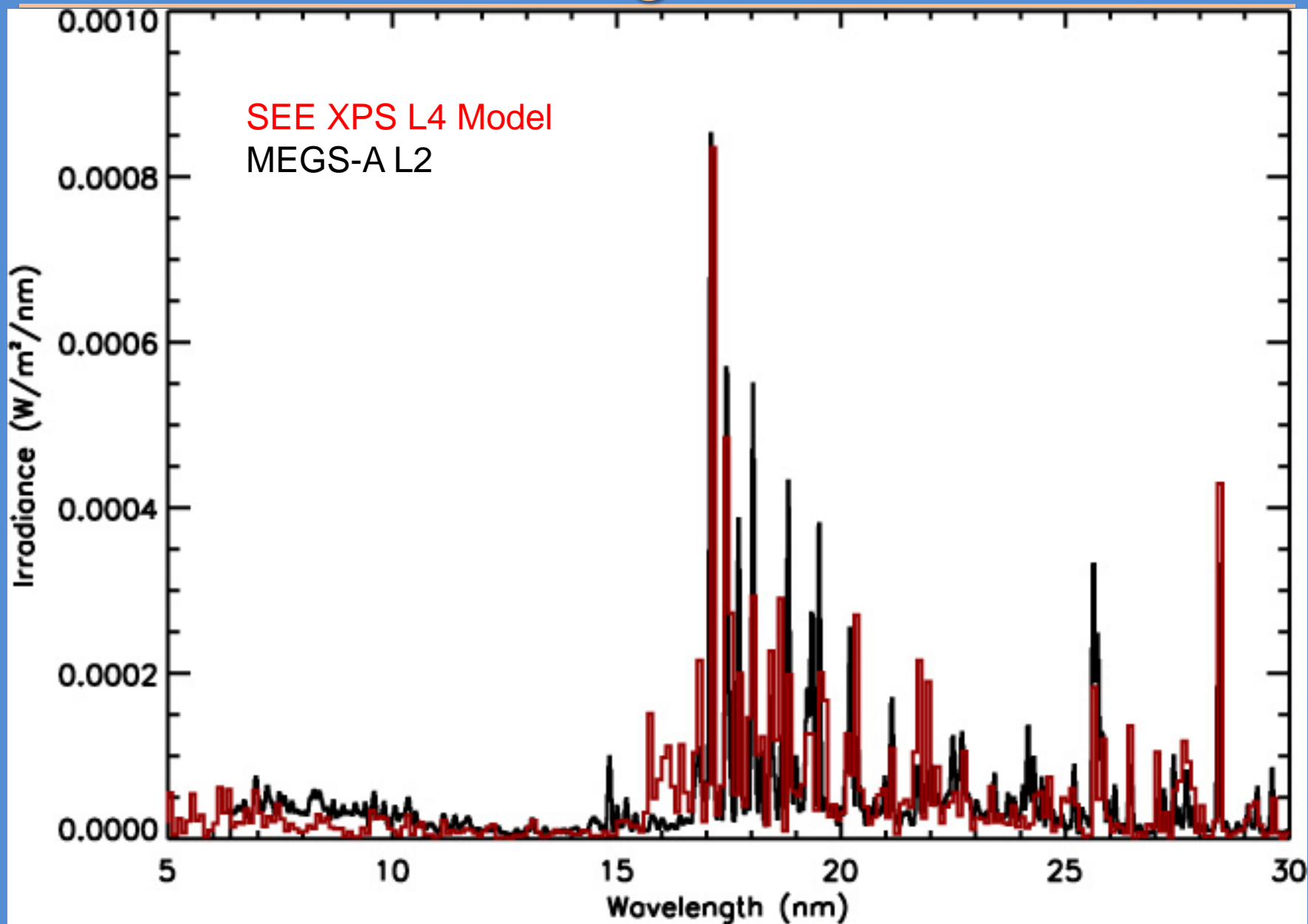
Same Thing, but Linear



MEGS-A and XPS L4



Same Thing, but Linear



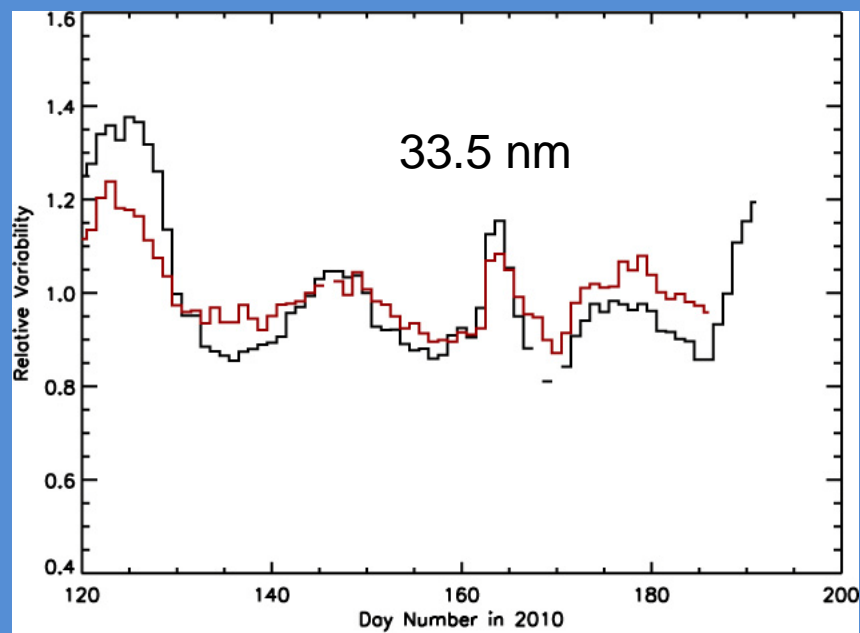
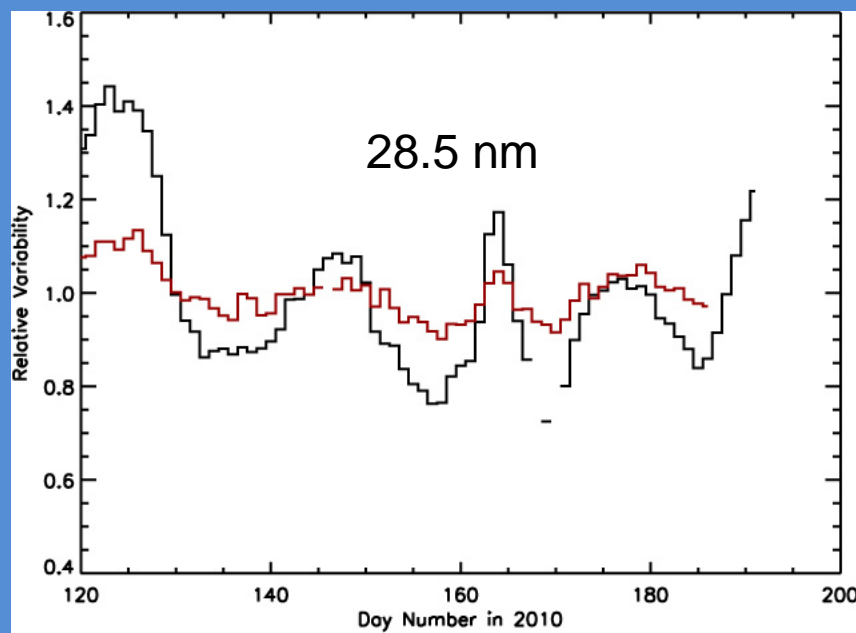
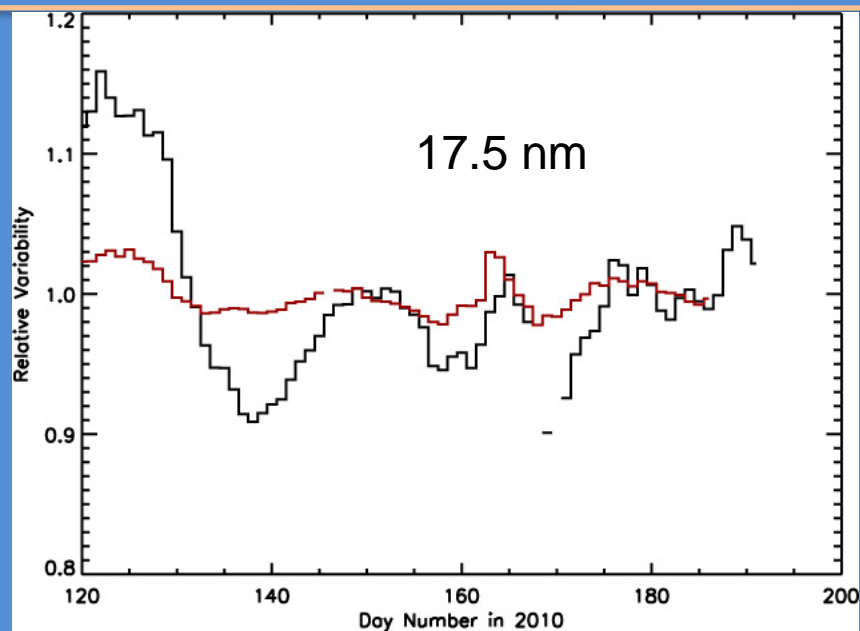
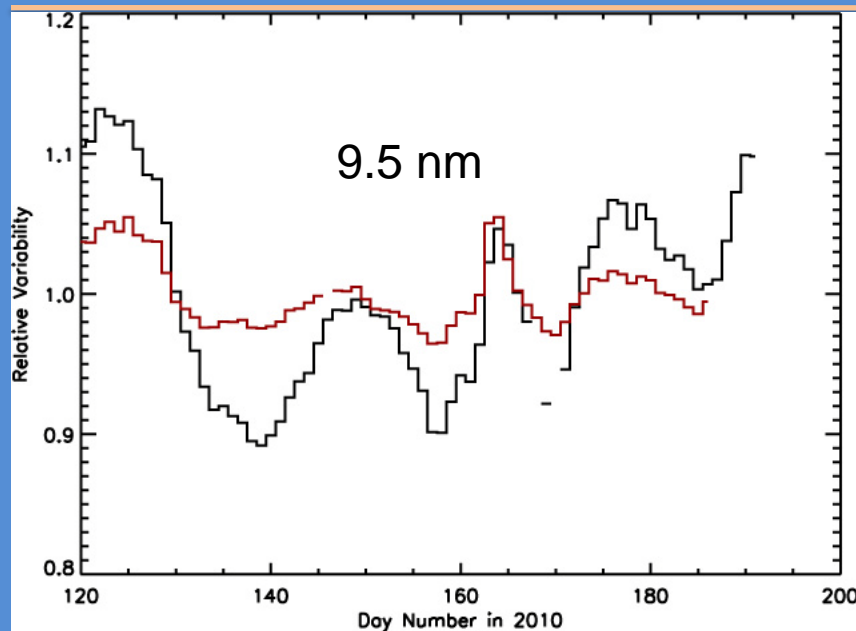
Conclusions to Spectra Comparison

- SEE EGS probably has a scattered light subtraction issue shortward of 33 nm
- SEE 30.4 nm line is lower than EVE by ~50%, but other lines agree well
- SEE XPS Model does surprisingly well
 - Line strengths don't match
 - This is a near solar minimum case only

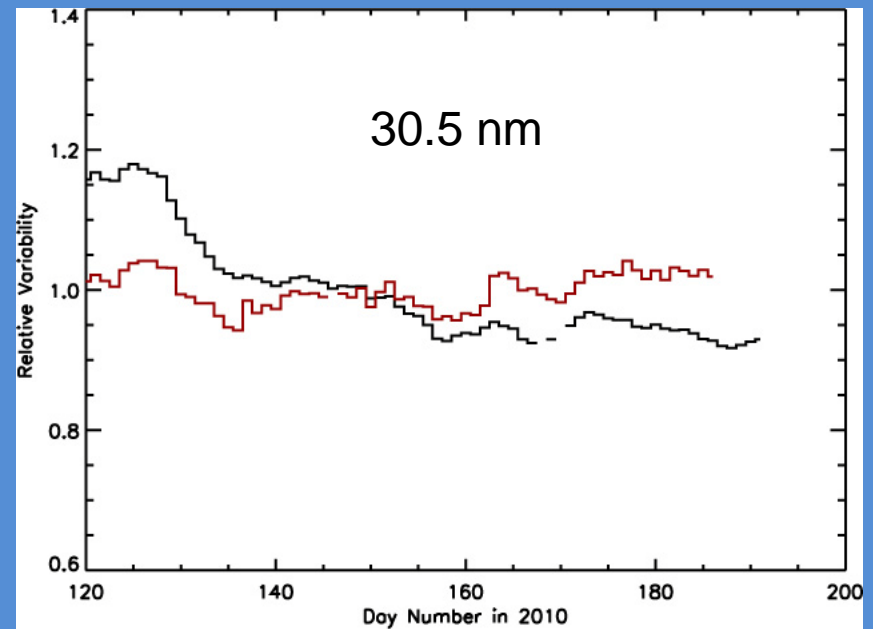
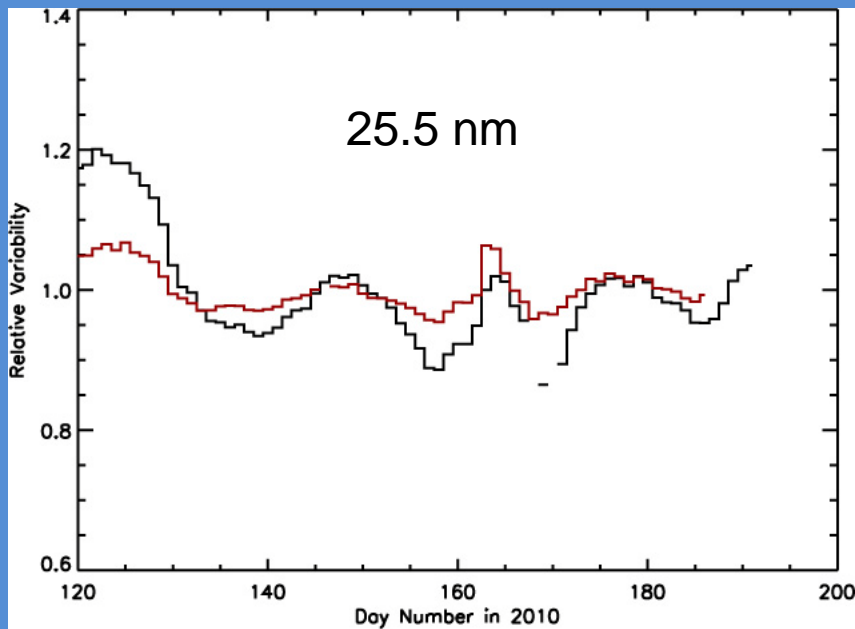
Next Look at Time Series

- Look at 1-nm binned data from both EVE and SEE
- Compare bins that are dominated by lines of similar variability (e.g. temperature)
- Normalize to mean value during period to show only variability

Coronal Line Bins



Transition-Region Line Bins



Conclusions to Time Series Comparisons

- Rotational variability matches better in general with EGS measured lines than XPS model
- There may be some degradation in MEGS at 30.4 nm, or SEE processing may be over-correcting 30.4 nm degradation (or both)

Summary

- Preliminary comparisons between SEE and EVE are pretty good.
- Differences seem to be more problems with SEE processing than with EVE.
- More comparisons with longer time series and with other instruments is needed for both EVE and SEE.
 - Unfortunately SEE is being turned off later this year.